



Welcome to [E-XFL.COM](#)

What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Obsolete
Core Processor	F ² MC-16FX
Core Size	16-Bit
Speed	32MHz
Connectivity	CANbus, I ² C, LINbus, SCI, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	52
Program Memory Size	96KB (96K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	10K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 21x8/10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (12x12)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/mb96f623rbpmc-gse2

■ A/D converter

- SAR-type
- 8/10-bit resolution
- Signals interrupt on conversion end, single conversion mode, continuous conversion mode, stop conversion mode, activation by software, external trigger, reload timers and PPGs
- Range Comparator Function

■ Source Clock Timers

Three independent clock timers (23-bit RC clock timer, 23-bit Main clock timer, 17-bit Sub clock timer)

■ Hardware Watchdog Timer

- Hardware watchdog timer is active after reset
- Window function of Watchdog Timer is used to select the lower window limit of the watchdog interval

■ Reload Timers

- 16-bit wide
- Prescaler with $1/2^1$, $1/2^2$, $1/2^3$, $1/2^4$, $1/2^5$, $1/2^6$ of peripheral clock frequency
- Event count function

■ Free-Running Timers

- Signals an interrupt on overflow, supports timer clear upon match with Output Compare (0, 4)
- Prescaler with 1 , $1/2^1$, $1/2^2$, $1/2^3$, $1/2^4$, $1/2^5$, $1/2^6$, $1/2^7$, $1/2^8$ of peripheral clock frequency

■ Input Capture Units

- 16-bit wide
- Signals an interrupt upon external event
- Rising edge, Falling edge or Both (rising & falling) edges sensitive

■ Output Compare Units

- 16-bit wide
- Signals an interrupt when a match with Free-running Timer occurs
- A pair of compare registers can be used to generate an output signal

■ Programmable Pulse Generator

- 16-bit down counter, cycle and duty setting registers
- Can be used as 2×8 -bit PPG
- Interrupt at trigger, counter borrow and/or duty match
- PWM operation and one-shot operation
- Internal prescaler allows 1 , $1/4$, $1/16$, $1/64$ of peripheral clock as counter clock or of selected Reload timer underflow as clock input
- Can be triggered by software or reload timer
- Can trigger ADC conversion
- Timing point capture

■ Quadrature Position/Revolution Counter (QPRC)

- Up/down count mode, Phase difference count mode, Count mode with direction
- 16-bit position counter
- 16-bit revolution counter
- Two 16-bit compare registers with interrupt
- Detection edge of the three external event input pins AIN, BIN and ZIN is configurable

■ Real Time Clock

- Operational on main oscillation (4MHz), sub oscillation (32kHz) or RC oscillation (100kHz/2MHz)
- Capable to correct oscillation deviation of Sub clock or RC oscillator clock (clock calibration)
- Read/write accessible second/minute/hour registers
- Can signal interrupts every half second/second/minute/hour/day
- Internal clock divider and prescaler provide exact 1s clock

■ External Interrupts

- Edge or Level sensitive
- Interrupt mask bit per channel
- Each available CAN channel RX has an external interrupt for wake-up
- Selected USART channels SIN have an external interrupt for wake-up

■ Non Maskable Interrupt

- Disabled after reset, can be enabled by Boot-ROM depending on ROM configuration block
- Once enabled, can not be disabled other than by reset
- High or Low level sensitive
- Pin shared with external interrupt 0

■ I/O Ports

- Most of the external pins can be used as general purpose I/O
- All push-pull outputs (except when used as I²C SDA/SCL line)
- Bit-wise programmable as input/output or peripheral signal
- Bit-wise programmable input enable
- One input level per GPIO-pin (either Automotive or CMOS hysteresis)
- Bit-wise programmable pull-up resistor

■ Built-in On Chip Debugger (OCD)

- One-wire debug tool interface
- Break function:
 - Hardware break: 6 points (shared with code event)
 - Software break: 4096 points
- Event function
 - Code event: 6 points (shared with hardware break)
 - Data event: 6 points
 - Event sequencer: 2 levels + reset
- Execution time measurement function
- Trace function: 42 branches
- Security function

■ Flash Memory

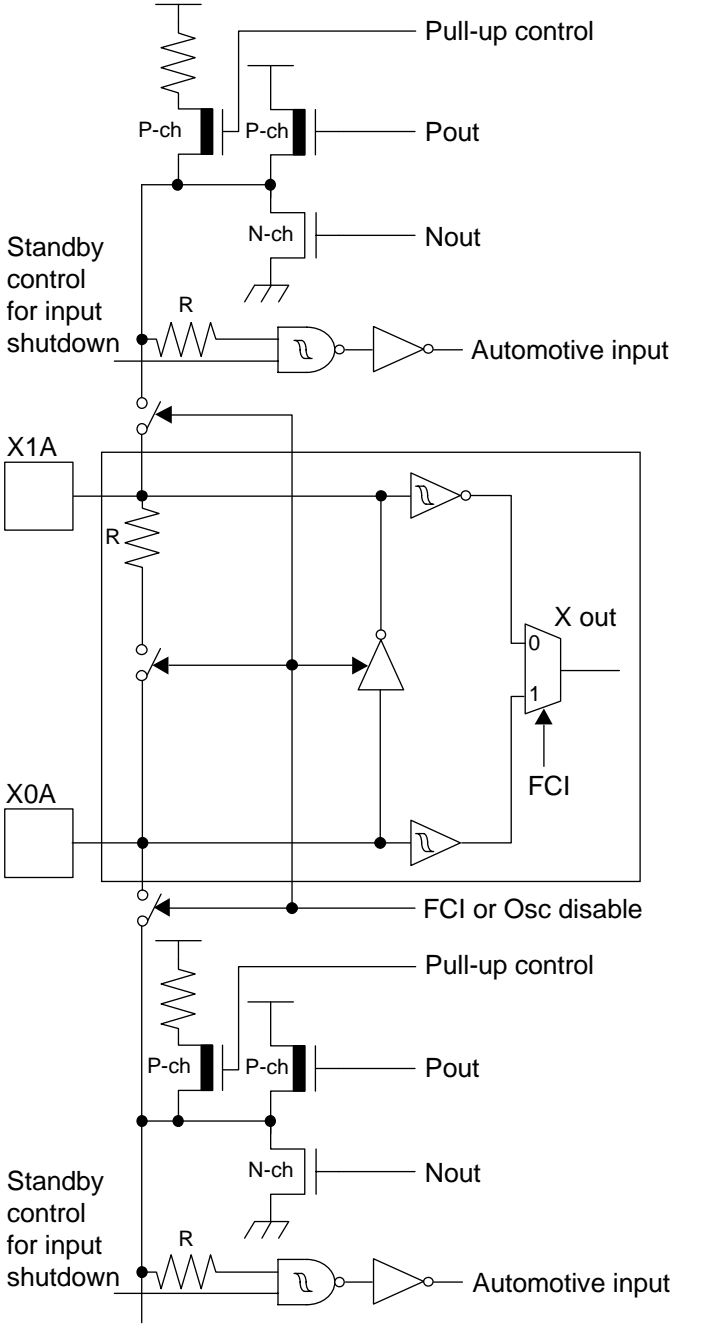
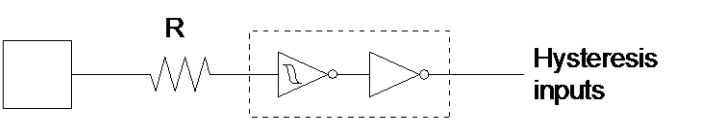
- Dual operation flash allowing reading of one Flash bank while programming or erasing the other bank
- Command sequencer for automatic execution of programming algorithm and for supporting DMA for programming of the Flash Memory
- Supports automatic programming, Embedded Algorithm
- Write/Erase/Erase-Suspend/Resume commands
- A flag indicating completion of the automatic algorithm
- Erase can be performed on each sector individually
- Sector protection
- Flash Security feature to protect the content of the Flash
- Low voltage detection during Flash erase or write

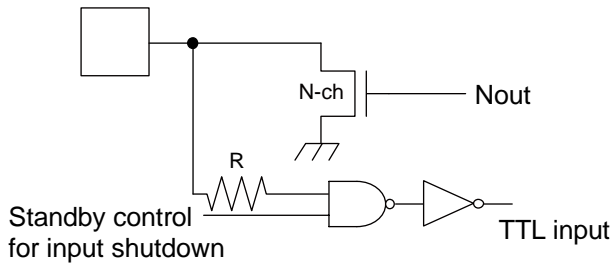
4. Pin Description

Pin name	Feature	Description
ADTG_R	ADC	Relocated A/D converter trigger input pin
AINn	QPRC	Quadrature Position/Revolution Counter Unit n input pin
ANn	ADC	A/D converter channel n input pin
AVcc	Supply	Analog circuits power supply pin
AVRH	ADC	A/D converter high reference voltage input pin
AVss	Supply	Analog circuits power supply pin
BINn	QPRC	Quadrature Position/Revolution Counter Unit n input pin
C	Voltage regulator	Internally regulated power supply stabilization capacitor pin
CKOTn	Clock Output function	Clock Output function n output pin
CKOTn_R	Clock Output function	Relocated Clock Output function n output pin
CKOTXn	Clock Output function	Clock Output function n inverted output pin
DEBUG I/F	OCD	On Chip Debugger input/output pin
FRCKn	Free-Running Timer	Free-Running Timer n input pin
INn	ICU	Input Capture Unit n input pin
INTn	External Interrupt	External Interrupt n input pin
INTn_R	External Interrupt	Relocated External Interrupt n input pin
INTn_R1	External Interrupt	Relocated External Interrupt n input pin
MD	Core	Input pin for specifying the operating mode
NMI_R	External Interrupt	Relocated Non-Maskable Interrupt input pin
OUTn	OCU	Output Compare Unit n waveform output pin
OUTn_R	OCU	Relocated Output Compare Unit n waveform output pin
Pnn_m	GPIO	General purpose I/O pin
PPGn	PPG	Programmable Pulse Generator n output pin (16bit/8bit)
PPGn_B	PPG	Programmable Pulse Generator n output pin (16bit/8bit)
RSTX	Core	Reset input pin
RXn	CAN	CAN interface n RX input pin
SCKn	USART	USART n serial clock input/output pin
SCKn_R	USART	Relocated USART n serial clock input/output pin
SCLn	I ² C	I ² C interface n clock I/O input/output pin
SDAn	I ² C	I ² C interface n serial data I/O input/output pin
SINn	USART	USART n serial data input pin
SINn_R	USART	Relocated USART n serial data input pin
SOTn	USART	USART n serial data output pin
SOTn_R	USART	Relocated USART n serial data output pin
TINn	Reload Timer	Reload Timer n event input pin
TOTn	Reload Timer	Reload Timer n output pin
TTGn	PPG	Programmable Pulse Generator n trigger input pin
TXn	CAN	CAN interface n TX output pin
Vcc	Supply	Power supply pin
Vss	Supply	Power supply pin

5. Pin Circuit Type

Pin no.	I/O circuit type*	Pin name
1	Supply	AVss
2	G	AVRH
3	K	P06_2 / AN2
4	K	P06_3 / AN3 / PPG3
5	K	P06_4 / AN4 / PPG4
6	K	P06_5 / AN5
7	K	P06_6 / AN6 / PPG6
8	K	P06_7 / AN7 / PPG7
9	I	P05_0 / AN8 / SIN2 / INT3_R1
10	K	P05_1 / AN9 / SOT2
11	I	P05_2 / AN10 / SCK2
12	K	P05_3 / AN11 / TIN3 / WOT
13	K	P05_4 / AN12 / TOT3 / INT2_R
14	K	P05_5 / AN13 / INT0_R / NMI_R
15	K	P05_6 / AN14 / INT4_R
16	H	P04_2 / IN6 / INT9_R / TTG6 / TTG14
17	H	P04_3 / IN7 / TTG7 / TTG15
18	Supply	Vss
19	B	P04_0 / X0A
20	B	P04_1 / X1A
21	C	MD
22	H	P17_0
23	O	DEBUG I/F
24	M	P00_0 / INT8 / SCK7_R / PPG0_B
25	H	P00_1 / INT9 / SOT7_R / PPG1_B
26	M	P00_2 / INT10 / SIN7_R
27	M	P00_3 / INT11 / SCK8_R / PPG3_B
28	H	P00_4 / INT12 / SOT8_R / PPG12_B
29	M	P00_5 / INT13 / SIN8_R / PPG14_B
30	H	P00_6 / INT14
31	H	P00_7 / INT15
32	H	P01_0 / TIN1 / CKOT1 / OUT0_R

Type	Circuit	Remarks
B	 <p>The diagram illustrates a low-speed oscillation circuit shared with GPIO functionality. It features a pull-up control, P-channel (P-ch) and N-channel (N-ch) transistors (Pout, Nout), a standby control for input shutdown, a feedback resistor R, an automotive input, and a multi-bit output X out with FCI control. The circuit is divided into two identical sections.</p>	<p>Low-speed oscillation circuit shared with GPIO functionality:</p> <ul style="list-style-type: none"> • Feedback resistor = approx. 5.0MΩ • GPIO functionality selectable (CMOS level output ($I_{OL} = 4\text{mA}$, $I_{OH} = -4\text{mA}$), Automotive input with input shutdown function and programmable pull-up resistor)
C	 <p>The diagram shows a CMOS hysteresis input pin circuit. It consists of a resistor R connected to a hysteresis input block.</p>	<p>CMOS hysteresis input pin</p>

Type	Circuit	Remarks
O		<ul style="list-style-type: none"> • Open-drain I/O • Output 25mA, $V_{CC} = 2.7V$ • TTL input

7. Memory Map

FF:FFFF _H	USER ROM* ¹
DE:0000 _H	
DD:FFFF _H	Reserved
10:0000 _H	
0F:C000 _H	Boot-ROM
0E:9000 _H	Peripheral
	Reserved
01:0000 _H	
00:8000 _H	ROM/RAM MIRROR
RAMSTART0* ²	Internal RAM bank0
	Reserved
00:0C00 _H	
00:0380 _H	Peripheral
00:0180 _H	GPR* ³
00:0100 _H	DMA
00:00F0 _H	Reserved
00:0000 _H	Peripheral

*1: For details about USER ROM area, see “USER ROM MEMORY MAP FOR FLASH DEVICES” on the following pages.

*2: For RAMSTART addresses, see the table on the next page.

*3: Unused GPR banks can be used as RAM area.

GPR: General-Purpose Register

The DMA area is only available if the device contains the corresponding resource.

The available RAM and ROM area depends on the device.

8. RAMSTART Addresses

Devices	Bank 0 RAM size	RAMSTART0
MB96F622	4KB	00:7200 _H
MB96F623 MB96F625	10KB	00:5A00 _H

10. Serial Programming Communication Interface

USART pins for Flash serial programming (MD = 0, DEBUG I/F = 0, Serial Communication mode)

MB96620		
Pin Number	USART Number	Normal Function
9	USART2	SIN2
10		SOT2
11		SCK2
26	USART7	SIN7_R
25		SOT7_R
24		SCK7_R
29	USART8	SIN8_R
28		SOT8_R
27		SCK8_R

12. Handling Precautions

Any semiconductor devices have inherently a certain rate of failure. The possibility of failure is greatly affected by the conditions in which they are used (circuit conditions, environmental conditions, etc.). This page describes precautions that must be observed to minimize the chance of failure and to obtain higher reliability from your Cypress semiconductor devices.

12.1 Precautions for Product Design

This section describes precautions when designing electronic equipment using semiconductor devices.

■ Absolute Maximum Ratings

Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of certain established limits, called absolute maximum ratings. Do not exceed these ratings.

■ Recommended Operating Conditions

Recommended operating conditions are normal operating ranges for the semiconductor device. All the device's electrical characteristics are warranted when operated within these ranges.

Always use semiconductor devices within the recommended operating conditions. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their sales representative beforehand.

■ Processing and Protection of Pins

These precautions must be followed when handling the pins which connect semiconductor devices to power supply and input/output functions.

1. Preventing Over-Voltage and Over-Current Conditions

Exposure to voltage or current levels in excess of maximum ratings at any pin is likely to cause deterioration within the device, and in extreme cases leads to permanent damage of the device. Try to prevent such overvoltage or over-current conditions at the design stage.

2. Protection of Output Pins

Shorting of output pins to supply pins or other output pins, or connection to large capacitance can cause large current flows. Such conditions if present for extended periods of time can damage the device. Therefore, avoid this type of connection.

3. Handling of Unused Input Pins

Unconnected input pins with very high impedance levels can adversely affect stability of operation. Such pins should be connected through an appropriate resistance to a power supply pin or ground pin.

■ Latch-up

Semiconductor devices are constructed by the formation of P-type and N-type areas on a substrate. When subjected to abnormally high voltages, internal parasitic PNP junctions (called thyristor structures) may be formed, causing large current levels in excess of several hundred mA to flow continuously at the power supply pin. This condition is called latch-up.

CAUTION: The occurrence of latch-up not only causes loss of reliability in the semiconductor device, but can cause injury or damage from high heat, smoke or flame. To prevent this from happening, do the following:

1. Be sure that voltages applied to pins do not exceed the absolute maximum ratings. This should include attention to abnormal noise, surge levels, etc.
2. Be sure that abnormal current flows do not occur during the power-on sequence.

■ Observance of Safety Regulations and Standards

Most countries in the world have established standards and regulations regarding safety, protection from electromagnetic interference, etc. Customers are requested to observe applicable regulations and standards in the design of products.

■ Fail-Safe Design

Any semiconductor devices have inherently a certain rate of failure. You must protect against injury, damage or loss from such failures by incorporating safety design measures into your facility and equipment such as redundancy, fire protection, and prevention of over-current levels and other abnormal operating conditions.

■ Precautions Related to Usage of Devices

Cypress semiconductor devices are intended for use in standard applications (computers, office automation and other office equipment, industrial, communications, and measurement equipment, personal or household devices, etc.).

CAUTION: Customers considering the use of our products in special applications where failure or abnormal operation may directly affect human lives or cause physical injury or property damage, or where extremely high levels of reliability are demanded (such as aerospace systems, atomic energy controls, sea floor repeaters, vehicle operating controls, medical devices for life support, etc.) are requested to consult with sales representatives before such use. The company will not be responsible for damages arising from such use without prior approval.

12.2 Precautions for Package Mounting

Package mounting may be either lead insertion type or surface mount type. In either case, for heat resistance during soldering, you should only mount under Cypress's recommended conditions. For detailed information about mount conditions, contact your sales representative.

■ Lead Insertion Type

Mounting of lead insertion type packages onto printed circuit boards may be done by two methods: direct soldering on the board, or mounting by using a socket.

Direct mounting onto boards normally involves processes for inserting leads into through-holes on the board and using the flow soldering (wave soldering) method of applying liquid solder. In this case, the soldering process usually causes leads to be subjected to thermal stress in excess of the absolute ratings for storage temperature. Mounting processes should conform to Cypress recommended mounting conditions.

If socket mounting is used, differences in surface treatment of the socket contacts and IC lead surfaces can lead to contact deterioration after long periods. For this reason it is recommended that the surface treatment of socket contacts and IC leads be verified before mounting.

■ Surface Mount Type

Surface mount packaging has longer and thinner leads than lead-insertion packaging, and therefore leads are more easily deformed or bent. The use of packages with higher pin counts and narrower pin pitch results in increased susceptibility to open connections caused by deformed pins, or shorting due to solder bridges.

You must use appropriate mounting techniques. Cypress recommends the solder reflow method, and has established a ranking of mounting conditions for each product. Users are advised to mount packages in accordance with Cypress ranking of recommended conditions.

■ Lead-Free Packaging

CAUTION: When ball grid array (BGA) packages with Sn-Ag-Cu balls are mounted using Sn-Pb eutectic soldering, junction strength may be reduced under some conditions of use.

■ Storage of Semiconductor Devices

Because plastic chip packages are formed from plastic resins, exposure to natural environmental conditions will cause absorption of moisture. During mounting, the application of heat to a package that has absorbed moisture can cause surfaces to peel, reducing moisture resistance and causing packages to crack. To prevent, do the following:

1. Avoid exposure to rapid temperature changes, which cause moisture to condense inside the product. Store products in locations where temperature changes are slight.
2. Use dry boxes for product storage. Products should be stored below 70% relative humidity, and at temperatures between 5°C and 30°C.
When you open Dry Package that recommends humidity 40% to 70% relative humidity.
3. When necessary, Cypress packages semiconductor devices in highly moisture-resistant aluminum laminate bags, with a silica gel desiccant. Devices should be sealed in their aluminum laminate bags for storage.
4. Avoid storing packages where they are exposed to corrosive gases or high levels of dust.

■ Baking

Packages that have absorbed moisture may be de-moisturized by baking (heat drying). Follow the Cypress recommended conditions for baking.

Condition: 125°C/24 h

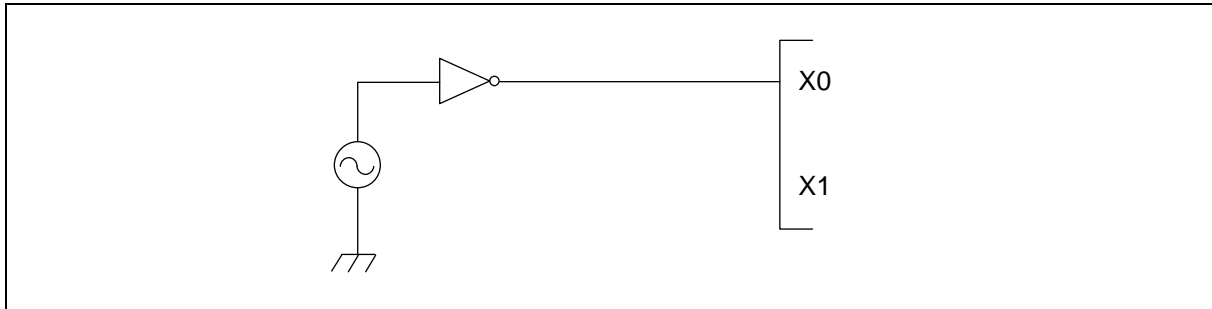
13.3 External clock usage

The permitted frequency range of an external clock depends on the oscillator type and configuration.

See AC Characteristics for detailed modes and frequency limits. Single and opposite phase external clocks must be connected as follows:

13.3.1 Single phase external clock for Main oscillator

When using a single phase external clock for the Main oscillator, X0 pin must be driven and X1 pin left open. And supply 1.8V power to the external clock.

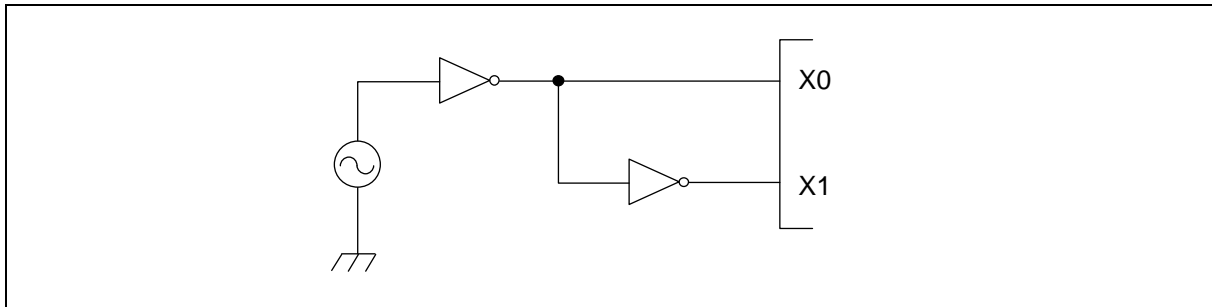


13.3.2 Single phase external clock for Sub oscillator

When using a single phase external clock for the Sub oscillator, "External clock mode" must be selected and X0A/P04_0 pin must be driven. X1A/P04_1 pin can be configured as GPIO.

13.3.3 Opposite phase external clock

When using an opposite phase external clock, X1 (X1A) pins must be supplied with a clock signal which has the opposite phase to the X0 (X0A) pins. Supply level on X0 and X1 pins must be 1.8V.



13.4 Notes on PLL clock mode operation

If the microcontroller is operated with PLL clock mode and no external oscillator is operating or no external clock is supplied, the microcontroller attempts to work with the free oscillating PLL. Performance of this operation, however, cannot be guaranteed.

13.5 Power supply pins (V_{CC}/V_{SS})

It is required that all V_{CC} -level as well as all V_{SS} -level power supply pins are at the same potential. If there is more than one V_{CC} or V_{SS} level, the device may operate incorrectly or be damaged even within the guaranteed operating range.

V_{CC} and V_{SS} pins must be connected to the device from the power supply with lowest possible impedance.

The smoothing capacitor at V_{CC} pin must use the one of a capacity value that is larger than C_s .

Besides this, as a measure against power supply noise, it is required to connect a bypass capacitor of about $0.1\mu F$ between V_{CC} and V_{SS} pins as close as possible to V_{CC} and V_{SS} pins.

13.6 Crystal oscillator and ceramic resonator circuit

Noise at X0, X1 pins or X0A, X1A pins might cause abnormal operation. It is required to provide bypass capacitors with shortest possible distance to X0, X1 pins and X0A, X1A pins, crystal oscillator (or ceramic resonator) and ground lines, and, to the utmost effort, that the lines of oscillation circuit do not cross the lines of other circuits.

It is highly recommended to provide a printed circuit board art work surrounding X0, X1 pins and X0A, X1A pins with a ground area for stabilizing the operation.

It is highly recommended to evaluate the quartz/MCU or resonator/MCU system at the quartz or resonator manufacturer, especially when using low-Q resonators at higher frequencies.

13.7 Turn on sequence of power supply to A/D converter and analog inputs

It is required to turn the A/D converter power supply (AV_{CC} , $AVRH$) and analog inputs (ANn) on after turning the digital power supply (V_{CC}) on.

It is also required to turn the digital power off after turning the A/D converter supply and analog inputs off. In this case, $AVRH$ must not exceed AV_{CC} . Input voltage for ports shared with analog input ports also must not exceed AV_{CC} (turning the analog and digital power supplies simultaneously on or off is acceptable).

13.8 Pin handling when not using the A/D converter

If the A/D converter is not used, the power supply pins for A/D converter should be connected such as $AV_{CC} = V_{CC}$, $AV_{SS} = AVRH = V_{SS}$.

13.9 Notes on Power-on

To prevent malfunction of the internal voltage regulator, supply voltage profile while turning the power supply on should be slower than 50 μ s from 0.2V to 2.7V.

13.10 Stabilization of power supply voltage

If the power supply voltage varies acutely even within the operation safety range of the V_{CC} power supply voltage, a malfunction may occur. The V_{CC} power supply voltage must therefore be stabilized. As stabilization guidelines, the power supply voltage must be stabilized in such a way that V_{CC} ripple fluctuations (peak to peak value) in the commercial frequencies (50Hz to 60Hz) fall within 10% of the standard V_{CC} power supply voltage and the transient fluctuation rate becomes 0.1V/ μ s or less in instantaneous fluctuation for power supply switching.

13.11 Serial communication

There is a possibility to receive wrong data due to noise or other causes on the serial communication.

Therefore, design a printed circuit board so as to avoid noise.

Consider receiving of wrong data when designing the system. For example apply a checksum and retransmit the data if an error occurs.

13.12 Mode Pin (MD)

Connect the mode pin directly to V_{CC} or V_{SS} pin. To prevent the device unintentionally entering test mode due to noise, lay out the printed circuit board so as to minimize the distance from the mode pin to V_{CC} or V_{SS} pin and provide a low-impedance connection.

14.3 DC Characteristics

14.3.1 Current Rating

($V_{CC} = AV_{CC} = 2.7V$ to $5.5V$, $V_{SS} = AV_{SS} = 0V$, $T_A = -40^{\circ}C$ to $+125^{\circ}C$)

Parameter	Symbol	Pin name	Conditions	Value			Unit	Remarks
				Min	Typ	Max		
Power supply current in Run modes ^{*1}	I _{CCPLL}	V _{CC}	PLL Run mode with CLKS1/2 = CLKB = CLKP1/2 = 32MHz	-	25	-	mA	T _A = +25°C
			Flash 0 wait	-	-	34	mA	T _A = +105°C
			(CLKRC and CLKSC stopped)	-	-	35	mA	T _A = +125°C
	I _{CCMAIN}		Main Run mode with CLKS1/2 = CLKB = CLKP1/2 = 4MHz	-	3.5	-	mA	T _A = +25°C
			Flash 0 wait	-	-	7.5	mA	T _A = +105°C
			(CLKPLL, CLKSC and CLKRC stopped)	-	-	8.5	mA	T _A = +125°C
	I _{CCRCH}		RC Run mode with CLKS1/2 = CLKB = CLKP1/2 = CLKRC = 2MHz	-	1.7	-	mA	T _A = +25°C
			Flash 0 wait	-	-	5.5	mA	T _A = +105°C
			(CLKMC, CLKPLL and CLKSC stopped)	-	-	6.5	mA	T _A = +125°C
	I _{CCRCL}		RC Run mode with CLKS1/2 = CLKB = CLKP1/2 = CLKRC = 100kHz	-	0.15	-	mA	T _A = +25°C
			Flash 0 wait	-	-	3.2	mA	T _A = +105°C
			(CLKMC, CLKPLL and CLKSC stopped)	-	-	4.2	mA	T _A = +125°C
	I _{CCSUB}		Sub Run mode with CLKS1/2 = CLKB = CLKP1/2 = 32kHz	-	0.1	-	mA	T _A = +25°C
			Flash 0 wait	-	-	3	mA	T _A = +105°C
			(CLKMC, CLKPLL and CLKRC stopped)	-	-	4	mA	T _A = +125°C

Parameter	Symbol	Pin name	Conditions	Value			Unit	Remarks
				Min	Typ	Max		
Power supply current in Sleep modes ^{*1}	I _{CCSPLL}	V _{CC}	PLL Sleep mode with CLKS1/2 = CLKP1/2 = 32MHz (CLKRC and CLKSC stopped)	-	6.5	-	mA	T _A = +25°C
				-	-	13	mA	T _A = +105°C
				-	-	14	mA	T _A = +125°C
	I _{CCSMAIN}		Main Sleep mode with CLKS1/2 = CLKP1/2 = 4MHz, SMCR:LPMSS = 0 (CLKPLL, CLKRC and CLKSC stopped)	-	0.9	-	mA	T _A = +25°C
				-	-	4	mA	T _A = +105°C
				-	-	5	mA	T _A = +125°C
	I _{CCSRCH}		RC Sleep mode with CLKS1/2 = CLKP1/2 = CLKRC = 2MHz, SMCR:LPMSS = 0 (CLKMC, CLKPLL and CLKSC stopped)	-	0.5	-	mA	T _A = +25°C
				-	-	3.5	mA	T _A = +105°C
				-	-	4.5	mA	T _A = +125°C
	I _{CCSRCL}		RC Sleep mode with CLKS1/2 = CLKP1/2 = CLKRC = 100kHz (CLKMC, CLKPLL and CLKSC stopped)	-	0.06	-	mA	T _A = +25°C
				-	-	2.7	mA	T _A = +105°C
				-	-	3.7	mA	T _A = +125°C
	I _{CCSSUB}		Sub Sleep mode with CLKS1/2 = CLKP1/2 = 32kHz, (CLKMC, CLKPLL and CLKRC stopped)	-	0.04	-	mA	T _A = +25°C
				-	-	2.5	mA	T _A = +105°C
				-	-	3.5	mA	T _A = +125°C

Parameter	Symbol	Pin name	Conditions	Value			Unit	Remarks
				Min	Typ	Max		
Power supply current in Stop mode*3	I _{CCH}	V _{CC}	-	-	20	55	μA	T _A = +25°C
				-	-	825	μA	T _A = +105°C
				-	-	1615	μA	T _A = +125°C
Flash Power Down current	I _{CCFLASHPD}		-	-	36	70	μA	
Power supply current for active Low Voltage detector*4	I _{CCLVD}		Low voltage detector enabled	-	5	-	μA	T _A = +25°C
				-	-	12.5	μA	T _A = +125°C
Flash Write/ Erase current*5	I _{CCFLASH}		-	-	12.5	-	mA	T _A = +25°C
				-	-	20	mA	T _A = +125°C

^{*1}: The power supply current is measured with a 4MHz external clock connected to the Main oscillator and a 32kHz external clock connected to the Sub oscillator. See chapter "Standby mode and voltage regulator control circuit" of the Hardware Manual for further details about voltage regulator control. Current for "On Chip Debugger" part is not included. Power supply current in Run mode does not include Flash Write / Erase current.

^{*2}: The power supply current in Timer mode is the value when Flash is in Power-down / reset mode.
When Flash is not in Power-down / reset mode, I_{CCFLASHPD} must be added to the Power supply current.

The power supply current is measured with a 4MHz external clock connected to the Main oscillator and a 32kHz external clock connected to the Sub oscillator. The current for "On Chip Debugger" part is not included.

^{*3}: The power supply current in Stop mode is the value when Flash is in Power-down / reset mode.
When Flash is not in Power-down / reset mode, I_{CCFLASHPD} must be added to the Power supply current.

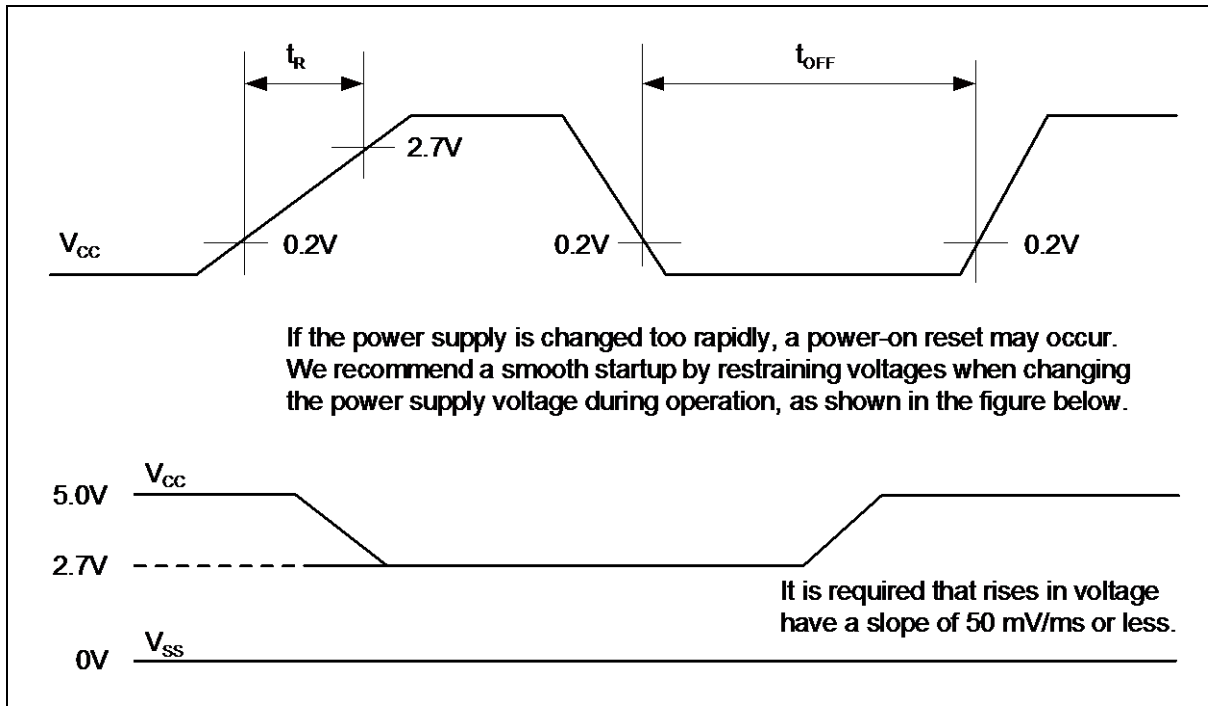
^{*4}: When low voltage detector is enabled, I_{CCLVD} must be added to Power supply current.

^{*5}: When Flash Write / Erase program is executed, I_{CCFLASH} must be added to Power supply current.

14.4.7 Power-on Reset Timing

($V_{CC} = AV_{CC} = 2.7V$ to $5.5V$, $V_{SS} = AV_{SS} = 0V$, $T_A = -40^{\circ}C$ to $+125^{\circ}C$)

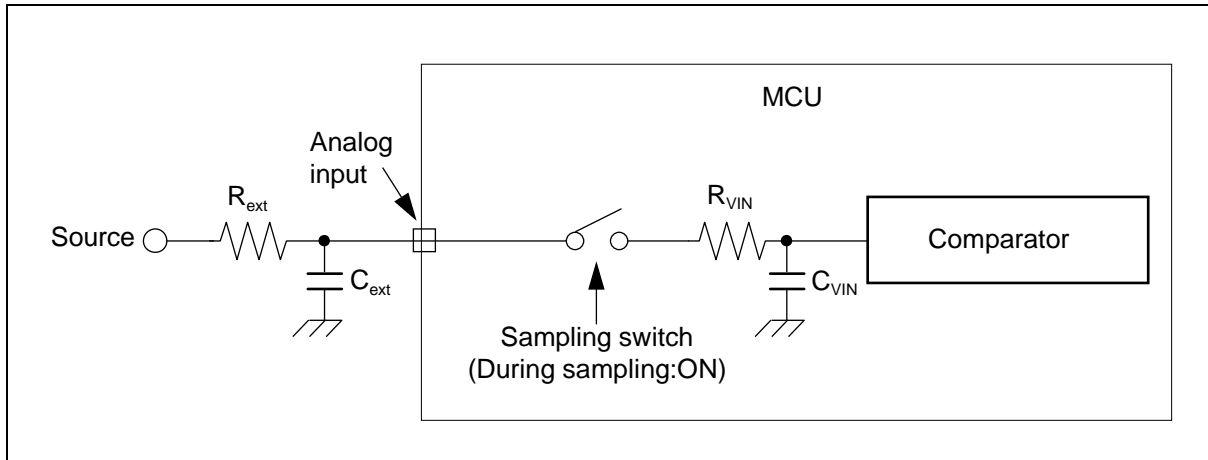
Parameter	Symbol	Pin name	Value			Unit
			Min	Typ	Max	
Power on rise time	t_R	V_{CC}	0.05	-	30	ms
Power off time	t_{OFF}	V_{CC}	1	-	-	ms



14.5.2 Accuracy and Setting of the A/D Converter Sampling Time

If the external impedance is too high or the sampling time too short, the analog voltage charged to the internal sample and hold capacitor is insufficient, adversely affecting the A/D conversion precision.

To satisfy the A/D conversion precision, a sufficient sampling time must be selected. The required sampling time (T_{samp}) depends on the external driving impedance R_{ext} , the board capacitance of the A/D converter input pin C_{ext} and the AV_{CC} voltage level. The following replacement model can be used for the calculation:



R_{ext} : External driving impedance

C_{ext} : Capacitance of PCB at A/D converter input

C_{VIN} : Analog input capacity (I/O, analog switch and ADC are contained)

R_{VIN} : Analog input impedance (I/O, analog switch and ADC are contained)

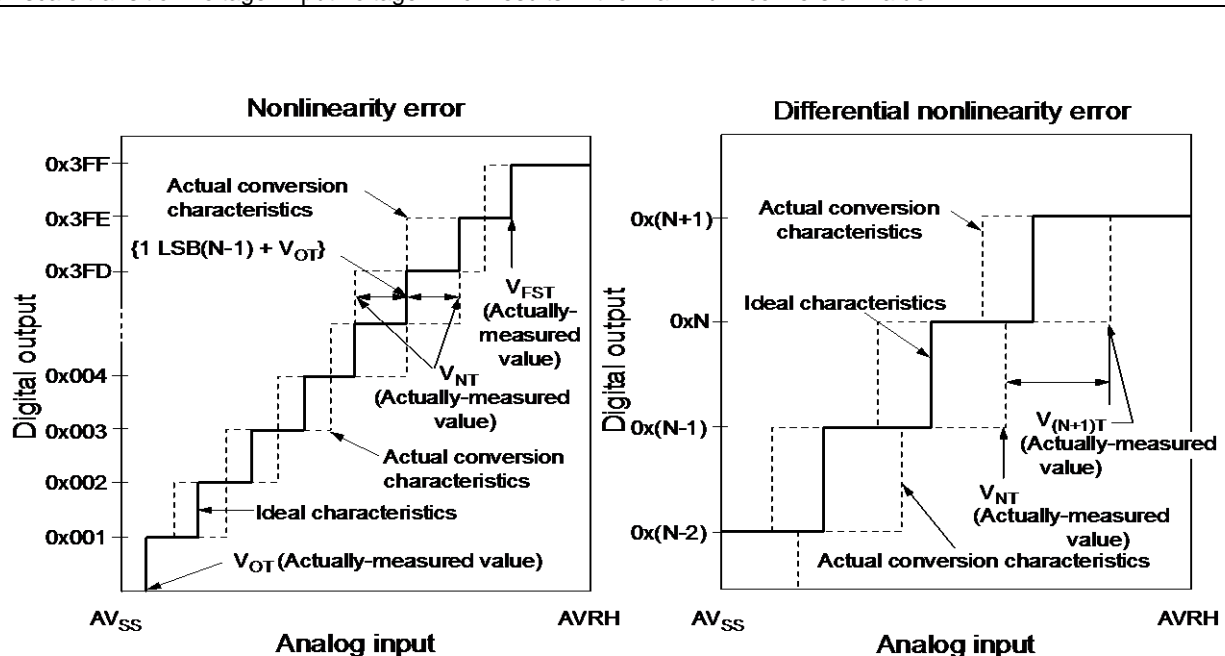
The following approximation formula for the replacement model above can be used:

$$T_{\text{samp}} = 7.62 \times (R_{\text{ext}} \times C_{\text{ext}} + (R_{\text{ext}} + R_{\text{VIN}}) \times C_{\text{VIN}})$$

- Do not select a sampling time below the absolute minimum permitted value.
($0.5\mu\text{s}$ for $4.5\text{V} \leq AV_{\text{CC}} \leq 5.5\text{V}$, $1.2\mu\text{s}$ for $2.7\text{V} \leq AV_{\text{CC}} < 4.5\text{V}$)
- If the sampling time cannot be sufficient, connect a capacitor of about $0.1\mu\text{F}$ to the analog input pin.
- A big external driving impedance also adversely affects the A/D conversion precision due to the pin input leakage current I_{IL} (static current before the sampling switch) or the analog input leakage current I_{AIN} (total leakage current of pin input and comparator during sampling). The effect of the pin input leakage current I_{IL} cannot be compensated by an external capacitor.
- The accuracy gets worse as $|AV_{\text{RH}} - AV_{\text{SS}}|$ becomes smaller.

14.5.3 Definition of A/D Converter Terms

- Resolution : Analog variation that is recognized by an A/D converter.
- Nonlinearity error : Deviation of the actual conversion characteristics from a straight line that connects the zero transition point (0b0000000000 \longleftrightarrow 0b0000000001) to the full-scale transition point (0b1111111110 \longleftrightarrow 0b1111111111).
- Differential nonlinearity error : Deviation from the ideal value of the input voltage that is required to change the output code by 1LSB.
- Total error : Difference between the actual value and the theoretical value. The total error includes zero transition error, full-scale transition error and nonlinearity error.
- Zero transition voltage : Input voltage which results in the minimum conversion value.
- Full scale transition voltage: Input voltage which results in the maximum conversion value.

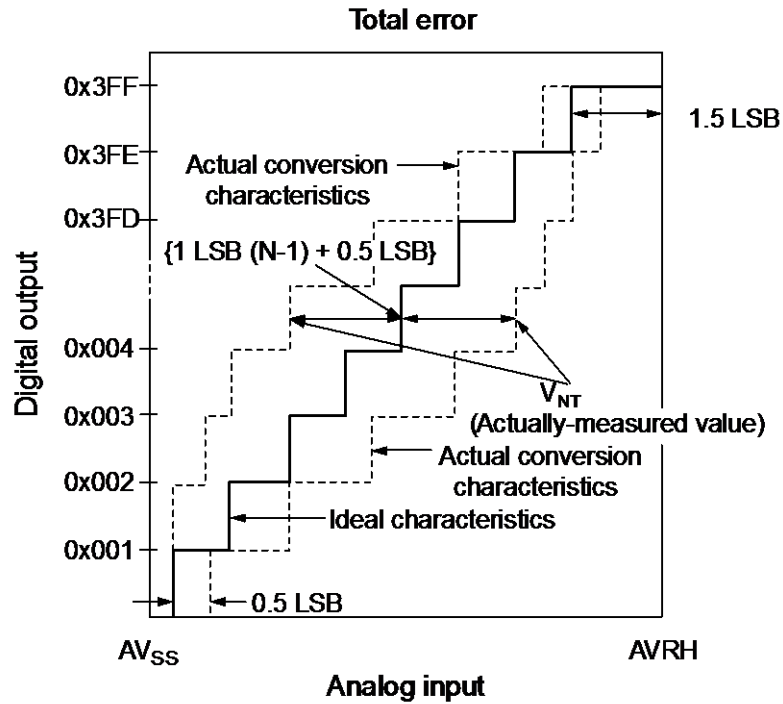


$$\text{Nonlinearity error of digital output } N = \frac{V_{NT} - \{1\text{LSB} \times (N - 1) + V_{OT}\}}{1\text{LSB}} \text{ [LSB]}$$

$$\text{Differential nonlinearity error of digital output } N = \frac{V_{(N+1)T} - V_{NT}}{1\text{LSB}} - 1 \text{ [LSB]}$$

$$1\text{LSB} = \frac{V_{FST} - V_{OT}}{1022}$$

- N : A/D converter digital output value.
- V_{OT} : Voltage at which the digital output changes from 0x000 to 0x001.
- V_{FST} : Voltage at which the digital output changes from 0x3FE to 0x3FF.
- V_{NT} : Voltage at which the digital output changes from 0x(N - 1) to 0xN.



$$1\text{LSB (Ideal value)} = \frac{AV_{RH} - AV_{SS}}{1024} \text{ [V]}$$

$$\text{Total error of digital output } N = \frac{V_{NT} - \{1\text{LSB} \times (N - 1) + 0.5\text{LSB}\}}{1\text{LSB}}$$

N : A/D converter digital output value.

V_{NT} : Voltage at which the digital output changes from $0x(N + 1)$ to $0xN$.

V_{OT} (Ideal value) = $AV_{SS} + 0.5\text{LSB}$ [V]

V_{FST} (Ideal value) = $AV_{RH} - 1.5\text{LSB}$ [V]

■ MB96F625

